## Application/Control No. Applicant(s)/Patent Under Reexamination MORGAN ET AL. Examiner Kevin M. Nguyen Applicant(s)/Patent Under Reexamination MORGAN ET AL. Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,222,515	04-2001	Yamaguchi et al.	345/89
	В	US-			
	С	US-			
	D	US-			
	E	US-			
	F	US-			
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	ı	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

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## **NON-PATENT DOCUMENTS**

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